

**Search Notes**

Application/Control No.

10/625,682

Examiner

M. Lee

Applicant(s)/Patent under  
Reexamination

CHOI ET AL.

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	730	3/29/2006	ML
	731		
	725		
	726		
	553		
	554		
725	131		
	139		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	3/29/2006	ML